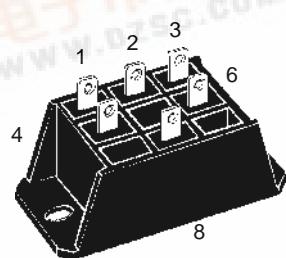
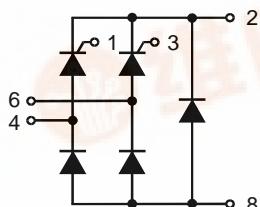




Half Controlled Single Phase Rectifier Bridge with Freewheeling Diode

$I_{dAVM} = 32 \text{ A}$
 $V_{RRM} = 800-1600 \text{ V}$

V_{RSM} V_{DSM}	V_{RRM} V_{DRM}	Type
V	V	
900	800	VHF 28-08i05
1300	1200	VHF 28-12i05
1500	1400	VHF 28-14i05
1700	1600	VHF 28-16i05



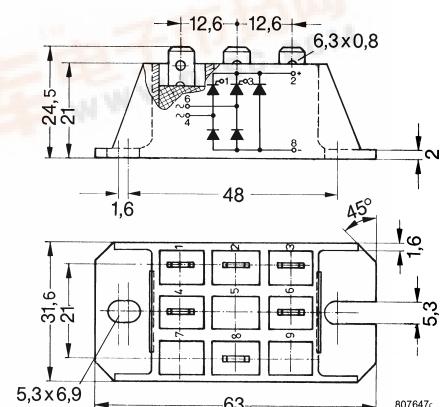
Symbol	Test Conditions	Maximum Ratings			Features
I_{dAV}	$T_K = 85^\circ\text{C}$, module	28	A		
I_{dAVM} ①	module	32	A		
I_{FRMS}, I_{TRMS}	per leg	23	A		
I_{FSM}, I_{TSM}	$T_{VJ} = 45^\circ\text{C}$; $V_R = 0 \text{ V}$	300	A		
	$t = 10 \text{ ms}$ (50 Hz), sine $t = 8.3 \text{ ms}$ (60 Hz), sine	330	A		
	$T_{VJ} = T_{VJM}$ $V_R = 0 \text{ V}$	270	A		
	$t = 10 \text{ ms}$ (50 Hz), sine $t = 8.3 \text{ ms}$ (60 Hz), sine	300	A		
I^2t	$T_{VJ} = 45^\circ\text{C}$ $V_R = 0 \text{ V}$	440	A^2s		
		455	A^2s		
	$T_{VJ} = T_{VJM}$ $V_R = 0 \text{ V}$	365	A^2s		
		370	A^2s		
$(di/dt)_{cr}$	$T_{VJ} = 125^\circ\text{C}$ $f = 50 \text{ Hz}, t_p = 200 \mu\text{s}$ $V_D = 2/3 V_{DRM}$ $I_G = 0.3 \text{ A}$, $di_G/dt = 0.3 \text{ A}/\mu\text{s}$	150	$\text{A}/\mu\text{s}$		
	repetitive, $I_T = 50 \text{ A}$				
	non repetitive, $I_T = 1/2 \cdot I_{dAV}$	500	$\text{A}/\mu\text{s}$		
$(dv/dt)_{cr}$	$T_{VJ} = T_{VJM}; V_{DR} = 2/3 V_{DRM}$ $R_{GK} = \infty$; method 1 (linear voltage rise)	1000	$\text{V}/\mu\text{s}$		
V_{RGM}		10	V		
P_{GM}	$T_{VJ} = T_{VJM}$ $I_T = I_{TAVM}$	$t_p = 30 \mu\text{s}$ $t_p = 500 \mu\text{s}$ $t_p = 10 \text{ ms}$	≤ 10 ≤ 5 ≤ 1	W	
P_{GAVM}			0.5	W	
T_{VJ}			-40...+125	$^\circ\text{C}$	
T_{VJM}			125	$^\circ\text{C}$	
T_{stg}			-40...+125	$^\circ\text{C}$	
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1 \text{ mA}$	$t = 1 \text{ min}$ $t = 1 \text{ s}$	3000 3600	V~	
M_d	Mounting torque (M5) (10-32 UNF)		2-2.5 18-22	Nm lb.in.	
Weight			50	g	

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.

① for resistive load

IXYS reserves the right to change limits, test conditions and dimensions.

Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
I_R, I_D	$V_R = V_{RRM}$; $V_D = V_{DRM}$	$T_{VJ} = T_{VJM}$	≤ 5	mA
		$T_{VJ} = 25^\circ C$	≤ 0.3	mA
V_T, V_F	$I_T, I_F = 45 A$; $T_{VJ} = 25^\circ C$		≤ 1.6	V
V_{TO}	For power-loss calculations only ($T_{VJ} = 125^\circ C$)			0.9 V
r_T			15	$m\Omega$
V_{GT}	$V_D = 6 V$;	$T_{VJ} = 25^\circ C$	≤ 1.0	V
		$T_{VJ} = -40^\circ C$	≤ 1.2	V
I_{GT}	$V_D = 6 V$;	$T_{VJ} = 25^\circ C$	≤ 65	mA
		$T_{VJ} = -40^\circ C$	≤ 80	mA
		$T_{VJ} = 125^\circ C$	≤ 50	mA
V_{GD}	$T_{VJ} = T_{VJM}$;	$V_D = 2/3 V_{DRM}$	≤ 0.2	V
I_{GD}	$T_{VJ} = T_{VJM}$;	$V_D = 2/3 V_{DRM}$	≤ 5	mA
I_L	$I_G = 0.3 A$; $t_G = 30 \mu s$; $di_G/dt = 0.3 A/\mu s$;	$T_{VJ} = 25^\circ C$	≤ 150	mA
		$T_{VJ} = -40^\circ C$	≤ 200	mA
		$T_{VJ} = 125^\circ C$	≤ 100	mA
I_H	$T_{VJ} = 25^\circ C$; $V_D = 6 V$; $R_{GK} = \infty$		≤ 100	mA
t_{gd}	$T_{VJ} = 25^\circ C$; $V_D = 1/2 V_{DRM}$ $I_G = 0.3 A$; $di_G/dt = 0.3 A/\mu s$		≤ 2	μs
t_g	$T_{VJ} = 125^\circ C$, $I_T = 15 A$, $t_p = 300 \mu s$, $V_R = 100 V$	typ.	150	μs
Q_r	$di/dt = -10 A/\mu s$, $dv/dt = 20 V/\mu s$, $V_D = 2/3 V_{DRM}$		75	μC
R_{thJC}	per thyristor (diode); DC current		1.4	K/W
	per module		0.35	K/W
R_{thJK}	per thyristor (diode); DC current		2.0	K/W
	per module		0.5	K/W
d_s	Creepage distance on surface		12.6	mm
d_a	Creepage distance in air		6.3	mm
a	Max. allowable acceleration		50	m/s^2

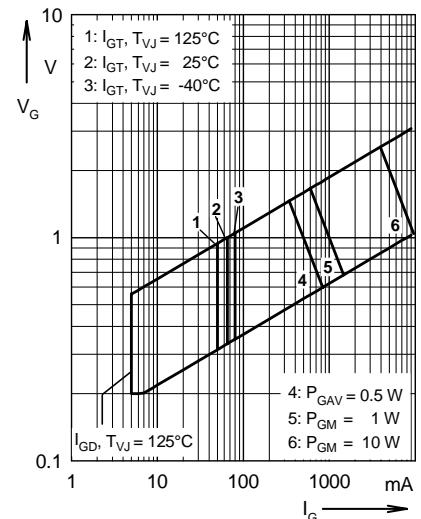
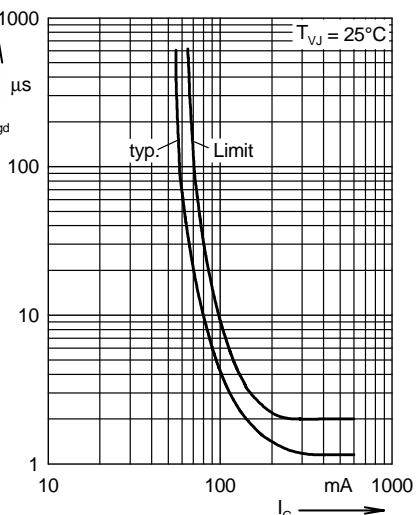


Fig. 1 Gate trigger range

Fig. 2 Gate controlled delay time t_{gd}

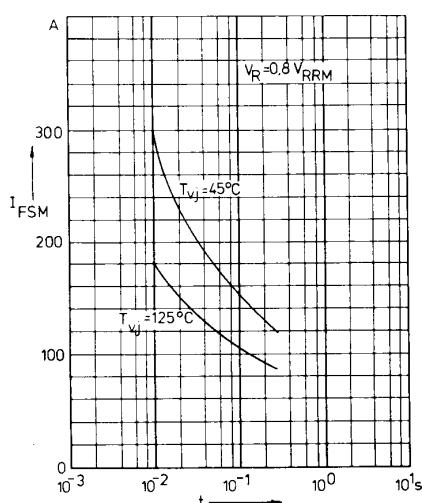


Fig. 3 Surge overload current per chip
 I_{FSM} : Crest value, t : duration

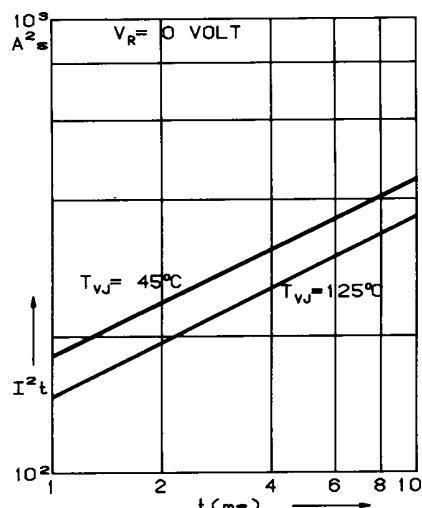


Fig. 4 I^2t versus time (1-10 ms)
per chip

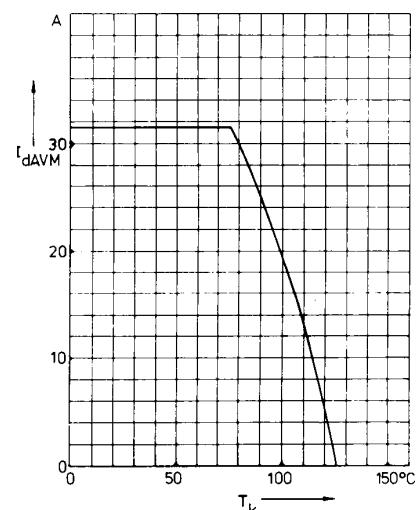


Fig. 5 Max. forward current at
heatsink temperature

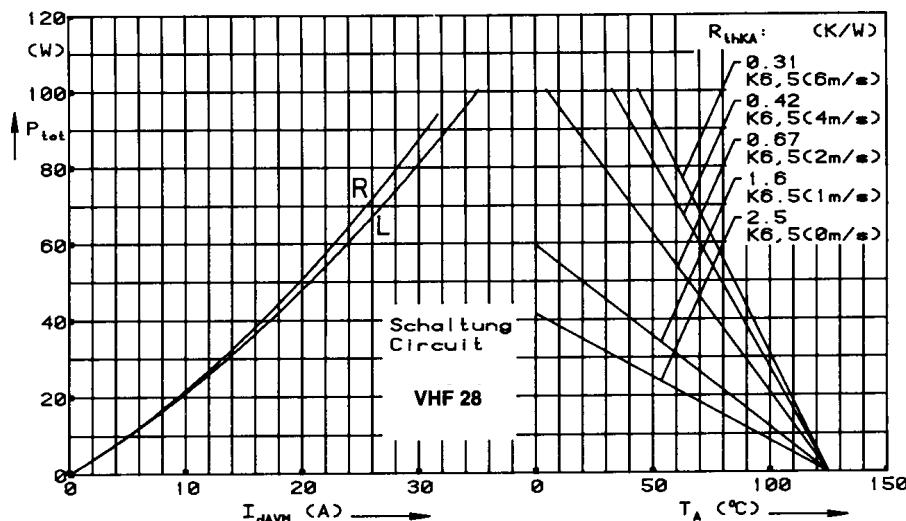


Fig. 6 Power dissipation versus direct output current and ambient temperature

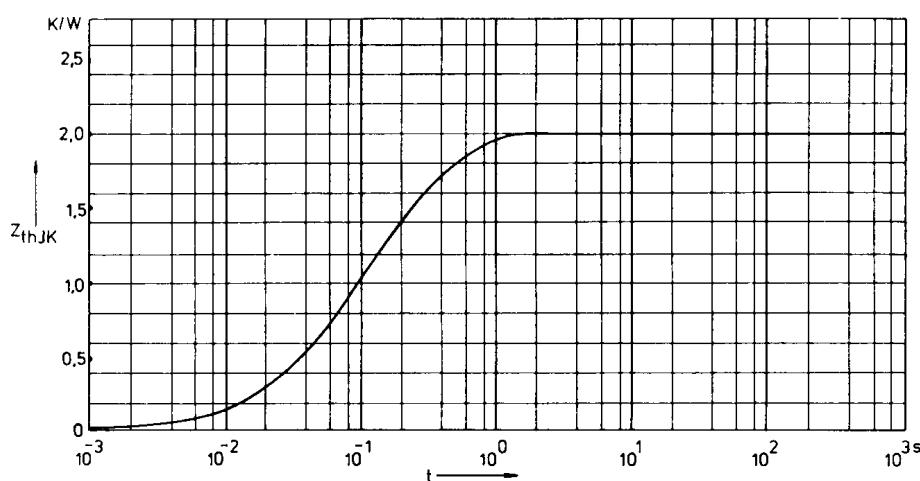


Fig. 7 Transient thermal impedance junction to heatsink per chip

Constants for Z_{thJK} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.3441	0.0344
2	1.1554	0.12
3	1.5005	0.5